## Sparch Notes

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Applicant(s)/Patent Under
Reexamination

2617

10522951 MUHONEN, JANNE

Art Unit Examiner

SEARCHED Class Subclass Date Examiner 455 458, 515, 516, 455, 464, 432, 435 2/16/10 SRB 456.1-457 455 7/15/2010 MC 455 404.2.414.2-414.3.456.1-457 11/14/2010 mc 342 455, 457 11/14/2010 mc 207 701 11/14/2010 mc

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SEARCH NOTES				
Search Notes	Date	Examiner		
EastImage keyword search in USPAT, USPGPUB, DERWENT, EPO,	2/16/10	SRB		
JPO, IBM_TDB (see attached search strategy)				
subclass search and text search	7/15/2010	MC		
subclass search, inventor search, interference search, PLUS search (east)	11/14/2010	mc		

INTERFERENCE SEARCH				
Class	Subclass	Date	Examiner	
455	404.2,414.2-414.3,456.1-457	11/14/2010	mc	
342	455, 457	11/14/2010	mc	
701	207	11/14/2010	mc	

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